

LANGER



IC-Scanner

FLS 102

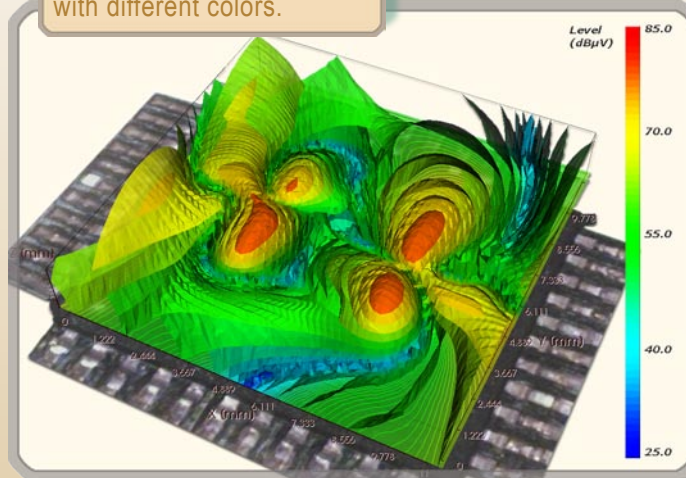
Measurement of radiated fields over the PCB IEC 61967-3



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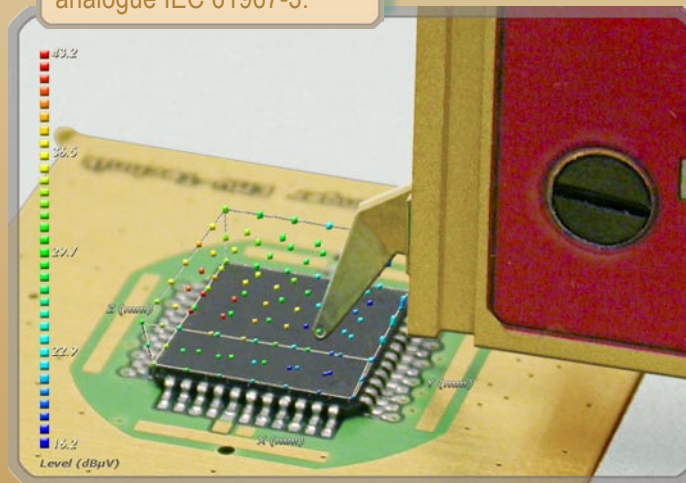
Chip Scan

Spatial visualization of the ISO-surfaces displays magnetic field intensity with different colors.



Volumen Scan

Measurement of the radiated emissions from PCB with the surface scan method analogue IEC 61967-3.

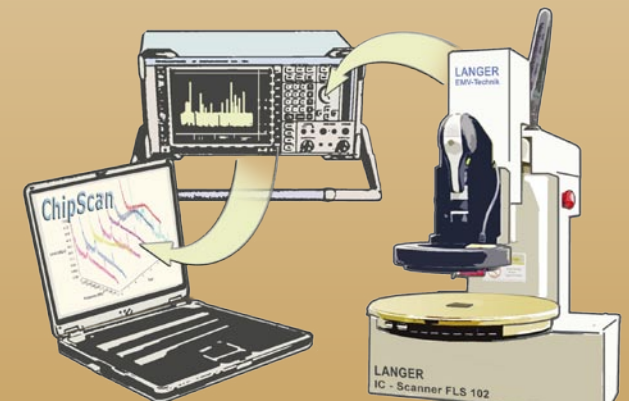


System specification

- | | | |
|--------------------------------|--|--|
| Measuring range: | FLS 102 | FLS 106 |
| x, y and z axes [mm] | 200x150x50 | 600x400x125 |
| rotation axis [rad]: | +/- 180° | +/- 180° |
| Alignment accuracy: | | |
| x, y and z axes: | 0.02 mm | 0.01 mm |
| rotation axis: | 1.0° | 1.0° |
| Near field microprobes: | | |
| - magnetic field | ICR HH 100 - 500 horizontal polarisation | ICR HV 100 - 500 vertical polarisation |
| - measurement resolution - min | 50 µm | |
| - electric field | ICR E 150 horizontal | |
| - with preamplifier | 30 dB / 50 Ohm | |
| - frequency range | 200 kHz up to 6 GHz | |

System architecture

- | | |
|--------------------------|---|
| Measuring probes: | Active near field microprobes |
| Measuring unit: | Spectrum analyzer |
| Control unit: | IBM compatible PC with Microsoft Windows® |
| Software: | ChipScan |



mail@langer-emv.de